

Measuring Sample Quality with Stein's Method

An attempt at quantifying Monte-Carlo efficiency by Gorham and Mackey (2015)

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Outline

Our goal is to calculate quantities of the form $\mathbb{E}_P[h(X)]$ where P is an unknown target distribution from the samples of Q as

$$\mathbb{E}_Q[h(X)] = \sum_{i=1}^n q(x_i)h(x_i).$$

We will be following (Gorham and Mackey, 2015).

- Revisiting Stein's Lemma
- Finding distances between distributions
- How Stein's method provides an answer
- Constructing Stein operators
- Calculating the discrepancies
- Experiments

Stein's Lemma

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$$X \sim \text{Poisson}(\lambda) \iff \mathbb{E}[\lambda f(X+1) - Xf(X)] = 0$$

$$X \sim \text{Binomial}(n, p) \iff \mathbb{E}[(1-p)Xf(X) - p(n-X)f(X+1)]$$

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$$X \sim P \iff \mathbb{E}_P[(\mathcal{A}f)(X)] = 0.$$

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Target distribution P with open convex support $\mathcal{X} \subseteq \mathbb{R}^d$. We approximate P with Q .

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How to ensure that calculating this expression is tractable?

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1. Find a real-valued operator $\mathcal{T} : \mathcal{G} \rightarrow \mathbb{R}$ characterizing P in the sense that

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Together, \mathcal{T}, \mathcal{G} define the *Stein discrepancy*

$$\mathcal{S}(Q, \mathcal{T}, \mathcal{G}) := \sup_{g \in \mathcal{G}} |\mathbb{E}_Q[(\mathcal{T}g)(X)]| = d_{\mathcal{G}}(Q, P).$$

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2. Lower bound \mathcal{S} by some familiar IPM $d_{\mathcal{H}}$. **Reliability:** for $\{\mu_m\}_{m \geq 1}$

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3. Upper bound $\mathcal{S}(Q, \mathcal{T}, \mathcal{G})$ to demonstrate convergence to zero (**Consistency**).

How to construct \mathcal{T}

Construct a generator for a Markov process $(Z_t)_{t \geq 0} \rightarrow P$ (Barbour, 1988). Consider a semigroup of operators $(\mathcal{A}_t f)(x) = \mathbb{E}[f(X_t) \mid X_0 = x]$. P is a limiting distribution if

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Stein Set

$$\mathcal{G}_{\|\cdot\|} = \left\{ g : \mathcal{X} \rightarrow \mathbb{R}^d \mid \sup_{x,y \in \mathcal{X}} \left(\|g\|^*, \|\nabla g\|^*, \frac{\|\nabla g(x) - \nabla g(y)\|^*}{\|x - y\|} \right) \leq 1, \langle g(x), \hat{n}(x) \rangle = 0, \forall x \in \partial \mathcal{X} \right\},$$

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Observation

This imposes conditions for all pairs of points in \mathcal{X} .

Bounding the Stein Discrepancy

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Lower bound:

Theorem (*Theorem 2*)

If $\mathcal{X} = \mathbb{R}^d$ and $\log p$ is strongly concave with continuous and bounded 3rd and 4th derivatives then for any measures $(\mu_m)_{m \geq 1}$, $\mathcal{S}(\mu_m, \mathcal{T}_P, \mathcal{G}_{\|\cdot\|}) \rightarrow 0$ only if $d_{\mathcal{W}}(\mu_m, P) \rightarrow 0$.

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Upper bound:

Theorem (Proposition 3)

If $X \sim Q$ and $Z \sim P$ with $\nabla \log p(Z)$ integrable, then

$$\begin{aligned}\mathcal{S}(Q, \mathcal{T}_P, \mathcal{G}_{\|\cdot\|}) &\leq \mathbb{E}\|X - Z\| + \mathbb{E}\|\nabla \log p(X) - \nabla \log p(Z)\| \\ &\quad + \mathbb{E}\|\nabla \log p(Z)(X - Z)^\top\|.\end{aligned}$$

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Implies convergence of $\mathcal{S} \rightarrow 0$ whenever $X_m \sim Q_m \xrightarrow{L^2} Z \sim P$ and $\nabla \log p(X_m) \xrightarrow{L^1} \nabla \log p(Z)$.

Computing Stein Discrepancies

For observed sample values $\{x_i\}_{i=1}^n$, we want to solve the optimization problem

$$\mathcal{S}(Q, \mathcal{T}_P, \mathcal{G}_{\|\cdot\|}) = \sup_{g \in \mathcal{G}_{\|\cdot\|}} \sum_{i=1}^n q(x_i) (\langle g(x_i), \nabla \log g(x_i) \rangle + \nabla \cdot g_{x_i}),$$

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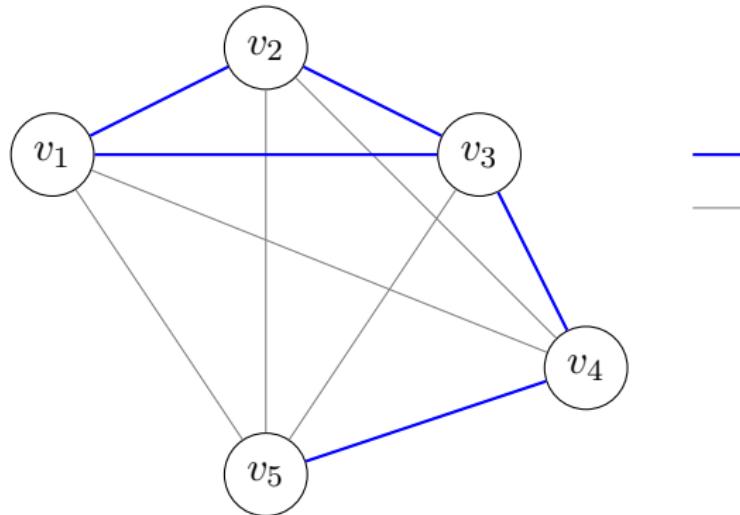
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$$\sup_{\gamma_j \in \mathbb{R}^n, \Gamma_j \in \mathbb{R}^{d \times n}} \sum_{i=1}^n q(x_i) (\langle \gamma_{ji}, \nabla \log \gamma_{ji} \rangle + \Gamma_{jji}),$$

for $\gamma_{ji} = g_j(x_i)$, $\Gamma_{jki} = \nabla_k g_j(x_i)$. An efficient way to define the constraints involves using *graph t-spanners* and an ℓ_1 norm.

Graph Spanners

Graph $G = K_5$ (Original)



t -Spanner Edges (G')
Original Edges (G)

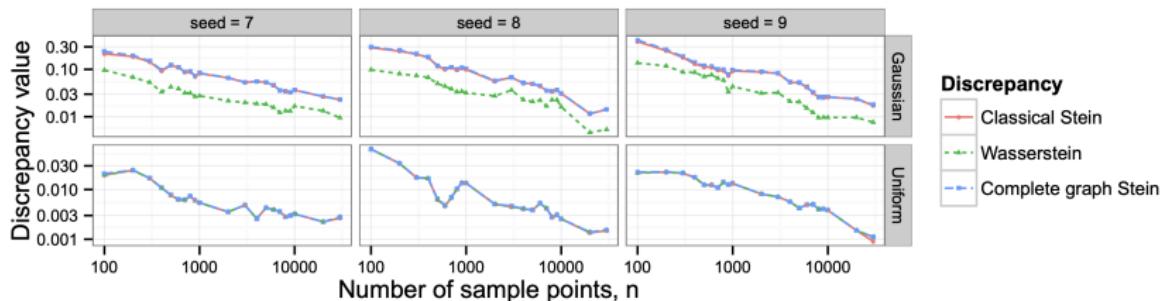
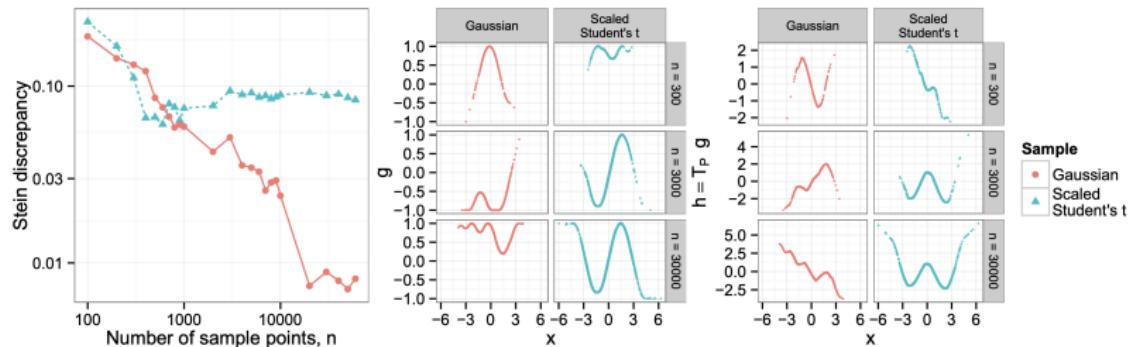
Graph G' (t -Spanner for $t \geq 1$)

Algorithm Multivariate Spanner Stein Discrepancy (Algorithm 1 in Gorham & Mackey 2015)

- 1: **input:** Q , coordinate bounds $(\alpha_1, \beta_1), \dots, (\alpha_d, \beta_d)$
 - 2: $G_2 \leftarrow$ Compute sparse 2-spanner of $\text{supp}(Q)$
 - 3: **for** $j = 1$ to d **do (parallelizable)**
 - 4: $r_j \leftarrow$ Solve the j -th coordinate from linear program (\star)
 - 5: **end for** $\sum_{j=1}^d r_j$
-

Experiments

Target distribution $P = \mathcal{N}(0, 1)$.



Extensions

- Change the diffusion process to generate \mathcal{T}_P .
- Replacing the calculation of \mathcal{S} with a Kernel Approach (Gorham and Mackey, 2017).
- Consider general diffusion operators (Gorham et al., 2019).
- If \mathcal{T}_P is too expensive to calculate, use *stochastic Stein discrepancies* (SSDs) (Gorham et al., 2020).
- And many others... (Anastasiou et al., 2023)

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